



## 3½ Digit A/D Converter

- ◆ Guaranteed Overload Recovery Time
- ◆ Significantly Improved ESD Protection (Note 7)
- ◆ Low Noise
- ◆ Key Parameters Guaranteed over Temperature
- ◆ Negligible Hysteresis
- ◆ Maxim Quality and Reliability
- ◆ Increased Maximum Rating for Input Current (Note 8)

**ABSOLUTE MAXIMUM RATINGS:** This device conforms to the Absolute Maximum Ratings on adjacent page.

**ELECTRICAL CHARACTERISTICS:** Specifications below satisfy or exceed all "tested" parameters on adjacent page.  
( $V^+ = 9V$ ;  $T_A = 25^\circ C$ ;  $f_{CLOCK} = 48kHz$ ; test circuit - Figure 1; unless noted)

PARAMETERS	CONDITIONS	MIN	TYP	MAX	UNITS
Zero Input Reading	$V_{IN} = 0.0V$ , Full Scale = 200.0mV $T_A = 25^\circ C$ (Note 6) $0^\circ \leq T_A \leq 70^\circ C$ (Note 10)	-000.0 -000.0	$\pm 000.0$ $\pm 000.0$	+000.0 +000.0	Digital Reading
Ratiometric Reading	$V_{IN} = V_{REF}$ , $V_{REF} = 100mV$ $T_A = 25^\circ C$ (Note 6) $0^\circ \leq T_A \leq 70^\circ C$ (Note 10)	999 998	999/1000 999/1000	1000 1001	Digital Reading
Rollover Error (Difference in reading for equal positive and negative reading near Full Scale)	$-V_{IN} = +V_{IN} \approx 200.0mV$ $T_A = 25^\circ C$ (Note 6) $0^\circ \leq T_A \leq 70^\circ C$ (Note 10)	-1	$\pm 2$ $\pm 2$	+1	Counts
Linearity (Max. deviation from best straight line fit)	Full Scale = 200.0mV or full scale = 2.000V	-1	$\pm 2$	+1	Counts
Common Mode Rejection Ratio	$V_{CM} = \pm 1V$ , $V_{IN} = 0V$ Full Scale = 200.0mV		50		$\mu V/V$
Noise (Pk-Pk value not exceeded 95% of time)	$V_{IN} = 0V$ Full Scale = 200.0mV		15		$\mu V$
Input Leakage Current	$V_{IN} = 0$ $T_A = 25^\circ C$ (Note 6) $0^\circ \leq T_A \leq 70^\circ C$		1 20	10 200	pA
Zero Reading Drift	$V_{IN} = 0$ $0^\circ \leq T_A \leq 70^\circ C$ (Note 6)		0.2	1	$\mu V/^\circ C$
Scale Factor Temperature Coefficient	$V_{IN} = 199.0mV$ $0^\circ \leq T_A \leq 70^\circ C$ (Ext. Ref. 0ppm/ $^\circ C$ ) (Note 6)		1	5	ppm/ $^\circ C$
V <sup>+</sup> Supply Current (Does not include LED current for 7107)	$V_{IN} = 0$ $T_A = 25^\circ C$ $0^\circ \leq T_A \leq 70^\circ C$		0.6	1.8 2	mA
V <sup>-</sup> Supply Current (7107 only)			0.6	1.8	mA
Analog Common Voltage (with respect to Pos. Supply)	25k $\Omega$ between Common & Pos. Supply	2.4	2.8	3.2	V
Temp. Coeff. of Analog Common (with respect to Pos. Supply)	25k $\Omega$ between Common & Pos. Supply		75		ppm/ $^\circ C$
7106 Only (Note 5) Pk-Pk Segment Drive Voltage, Pk-Pk Backplane Drive Voltage	$V^+$ to $V^- = 9V$	4	5	6	V
7107 Only—Segment Sinking Current (Except Pin 19) (Pin 19 only)	$V^+ = 5.0V$ Segment Voltage = 3V	5 10	8.0 16		mA mA
7106 Only—Test Pin Voltage	With Respect to $V^+$	4	5	6	V
Overload Recovery Time (Note 9)	$V_{IN}$ changing from $\pm 10V$ to 0V		0	1	Measurement Cycles

Note 6: Test condition is  $V_{IN}$  applied between pin IH-HI and IN-LO through a 1M $\Omega$  series resistor as shown in Figures 1 and 2.

Note 7: All pins are designed to withstand electrostatic discharge (ESD) levels in excess of 2000V. (Test circuit per Mil Std 883, Method 3015.1)

Note 8: Input voltages may exceed the supply voltage provided the input current is limited to  $\pm 1mA$  (This revises Note 1 on adjacent page).

Note 9: Number of measurement cycles for display to give accurate reading.

Note 10: 1M $\Omega$  resistor is removed in Figures 1 and 2.



ICL7106/7107